

<b>Notice of References Cited</b>	Application/Control No. 10/006,044		Applicant(s)/Patent Under Reexamination SIH ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,313,766	11-2001	Langendorf et al.	341/67
	B	US-6,335,950	01-2002	Kohn, Leslie	375/240.16
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP1146746	<del>06-2000</del> 10-2001	EPC	Kohashi et al.	H04N 7/24
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
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	X	

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